


<b>Search Notes</b>  	<b>Application/Control No.</b>  10511863	<b>Applicant(s)/Patent Under Reexamination</b>  NAIM ET AL.
	<b>Examiner</b>  Nguyen, Huy D	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
455	411, 410, 445, 432.1, 432.2, 433, 552.1, 553.1, 426.1, 435.1, 435.2,	2/6/2008	HN
370	466, 467	2/6/2008	HN
713	168, 171, 172, 176	2/6/2008	HN
380	258	2/6/2008	HN

SEARCH NOTES		
Search Notes	Date	Examiner
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	02/06/2008	HN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner